

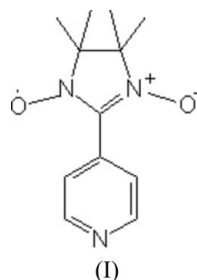
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Key indicators

Single-crystal X-ray study
 $T = 293$ K
Mean $\sigma(\text{C}-\text{C}) = 0.005$ Å
 R factor = 0.079
 wR factor = 0.206
Data-to-parameter ratio = 15.5For details of how these key indicators were
automatically derived from the article, see
<http://journals.iucr.org/e>.4,4,5,5-Tetramethyl-2-(4-pyridyl)imidazolin-
1-oxyl 3-oxideThe molecular structure of the title radical compound,
 $\text{C}_{12}\text{H}_{16}\text{N}_3\text{O}_2$, has crystallographic C_2 symmetry. The dihedral
angle between the pyridine and imidazole rings is 25.66 (15)°.

Comment

Nitroxide radicals are widely used to prepare molecule-based
magnetic materials (Vostrikova *et al.*, 2000; Oshio *et al.*, 2002).
We report here the synthesis and crystal structure of the title
radical compound, (I).The molecular structure of (I) is shown in Fig. 1. The
molecule has crystallographic C_2 symmetry, the C3—C4 bond,
atom N1 and the mid-point of the C5—C5A bond being
located on a twofold axis. The pyridine ring is twisted with
respect to the imidazole ring with a dihedral angle of
 25.66 (15)°.

Experimental

The title compound was prepared according to the method reported
by Ullman *et al.* (1974). 2,3-Dimethyl-2,3-bis(hydroxylamino)butane
and 4-pyridinecarbaldehyde were dissolved in a methanol solution
which was stirred for 1 h at room temperature, and then filtered.
Single crystals of (I) were obtained from the filtrate.

Crystal data

$\text{C}_{12}\text{H}_{16}\text{N}_3\text{O}_2$	$Z = 4$
$M_r = 234.28$	$D_x = 1.267$ Mg m ⁻³
Monoclinic, $C2/c$	Mo $K\alpha$ radiation
$a = 11.205$ (7) Å	$\mu = 0.09$ mm ⁻¹
$b = 10.452$ (7) Å	$T = 293$ (2) K
$c = 11.031$ (8) Å	Block, blue
$\beta = 108.051$ (11)°	$0.24 \times 0.20 \times 0.16$ mm
$V = 1228.3$ (14) Å ³	

Data collection

Bruker SMART CCD area-detector	1258 independent reflections
detector diffractometer	655 reflections with $I > 2\sigma(I)$
φ and ω scans	$R_{\text{int}} = 0.088$
Absorption correction: none	$\theta_{\text{max}} = 26.5^\circ$
3365 measured reflections	

Refinement

Refinement on F^2

$$R[F^2 > 2\sigma(F^2)] = 0.079$$

$$wR(F^2) = 0.206$$

$$S = 1.03$$

1258 reflections

81 parameters

H-atom parameters constrained

$$w = 1/[\sigma^2(F_o^2) + (0.09P)^2]$$

$$\text{where } P = (F_o^2 + 2F_c^2)/3$$

$$(\Delta/\sigma)_{\max} = 0.002$$

$$\Delta\rho_{\max} = 0.23 \text{ e } \text{\AA}^{-3}$$

$$\Delta\rho_{\min} = -0.26 \text{ e } \text{\AA}^{-3}$$

Methyl H atoms were placed in calculated positions, with C–H = 0.96 Å, and torsion angles were refined to fit the electron density, $U_{\text{iso}}(\text{H}) = 1.5U_{\text{eq}}(\text{C})$. Aromatic H atoms were placed in calculated positions, with C–H = 0.93 Å, and refined in riding mode with $U_{\text{iso}}(\text{H}) = 1.2U_{\text{eq}}(\text{C})$.

Data collection: *SMART* (Bruker, 1999); cell refinement: *SAINTE* (Bruker, 1999); data reduction: *SAINTE*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Bruker, 1997); software used to prepare material for publication: *SHELXTL*.

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References

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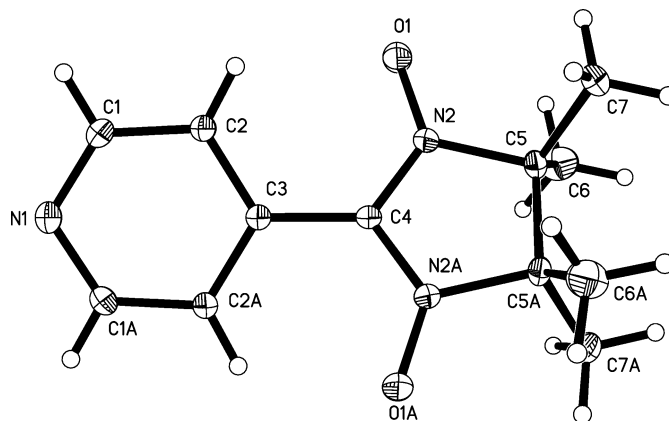


Figure 1

The molecular structure of (I) with 15% probability displacement ellipsoids (arbitrary spheres for H atoms) [symmetry code: (A) $-x, y, -z + \frac{1}{2}$].

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